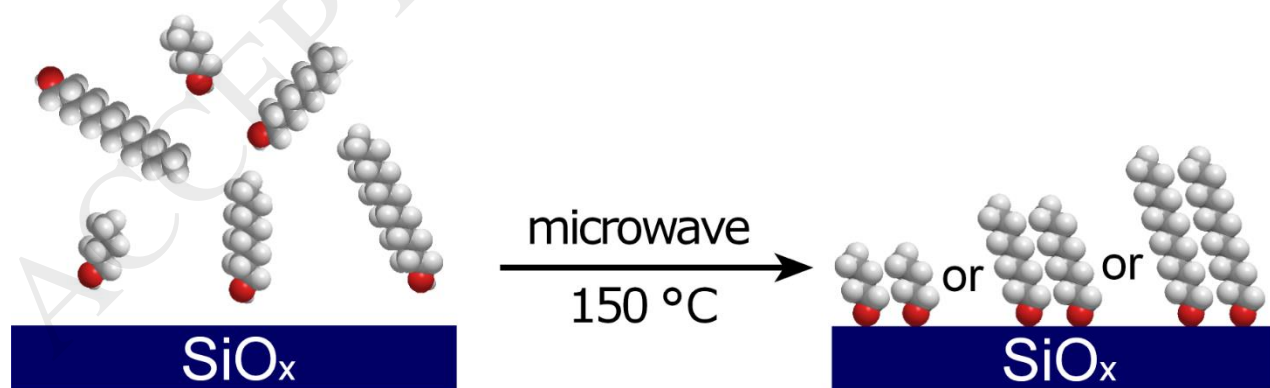


**Determining the Thickness of Aliphatic Alcohol Monolayers Covalently Attached to Silicon
Oxide Surfaces Using Angle-Resolved X-ray Photoelectron Spectroscopy**

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Graphical abstract



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